

EV 979950225

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Reissue Application Serial No. .... Filed Concurrently  
Reissue Filing Date .... Filed Concurrently  
Inventor .... Mark E. Tuttle et al.  
Assignee .... Micron Technology, Inc.  
Patent No. .... 6,329,213 B1  
Issued .... December 11, 2001  
Group Art Unit .... Unassigned  
Examiner .... Unassigned  
Attorney's Docket No. .... MI40-369  
Title: Methods for Forming Integrated Circuits within Substrates

**INFORMATION DISCLOSURE STATEMENT**

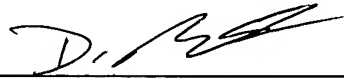
References - - See attached Form PTO-1449

The citations listed may be material to the examination of the subject application and are therefore submitted in compliance with the duty of disclosure defined in 37 CFR § 1.56. Copies of the foreign patents are attached.

Respectfully submitted,

Date: Dec. 10, 2003

Attorney:

  
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Deepak Malhotra  
Reg. No. 33,560

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI40-369		SERIAL NO. UNASSIGNED	
<b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)				APPLICANT MICRON TECHNOLOGY, INC.			
				FILING DATE FILED HEREWITH		GROUP UNASSIGNED	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	3,701,317	10/1972	MIYAMOTO ET AL.	101	170	
	AB	3,981,761	9/1976	KOJIMA ET AL.	156	235	
	AC	4,075,632	2/1978	BALDWIN ET AL.	343	68 R	
	AD	4,135,184	1/1979	PRUZICK	340	572	
	AE	4,232,512	11/1980	YOSHIKAWA ET AL.	368	82	
	AF	4,926,182	5/15/90	OHTA ET AL.	342	44	
	AG	5,148,355	9/1992	LOWE ET AL.	361	410	
	AH	5,402,095	3/28/95	JANNIERE	235	441	
	AI	5,412,192	5/1995	HOSS	235	380	
	AJ	5,428,214	6/1995	HAKKERS ET AL.	235	492	
	AK	5,528,222	6/1996	MOSKOWITZ ET AL.	340	572	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes      No
	AL	WO 96/07985	3/1996	PCT			
	AM	0 682 321	5/1995	Europe			
	AN	DE 4431605	3/1996	German			
	AO	DE 3201065	7/1993	German			
	AP	WO 90 07858	7/1990	PCT			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER				DATE CONSIDERED			
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U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,598,032	1/1997	FIDALGO	257	679	
	AB	5,600,175	2/1997	ORTHMANN	257	532	
	AC	5,621,412	4/1997	SHARPE ET AL.	342	51	
	AD	5,647,122	7/1997	LAUNAY ET AL.	29	840	
	AE	5,649,296	7/15/97	MACLELLAN ET AL.	455	38.2	
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	AG	5,735,040	4/1998	OCHI ET AL.	29	841	
	AH	5,850,690	12/1998	LAUNAY ET AL.	29	841	
	AI	5,880,934	3/1999	HAGHIRI-TEHRANI	361	737	
	AJ	5,880,937	3/1999	SCHADHAUSER ET AL.	361	794	
	AK	6,130,602	10/2000	O'TOOLE ET AL.	340	10.33	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes      No
	AL	8-138022	5/1996	JAPAN			*
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	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
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